

**Search Notes**

Application/Control No.

10/725,325

Examiner

Steven Loke

Applicant(s)/Patent under  
Reexamination

HSHIEH ET AL.

Art Unit

2811

**SEARCHED**

Class	Subclass	Date	Examiner
257	341,	5/13/05	Loke
	342,		
	329,		
	330,		
	331		
438	212,		
	259,		
	270,		
	271,		
	589,		
	588,		
	587		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR